Using Simulation and Graphics as an Aid in Planning Complicated Experiments Joint Research Conference June 8, 2006

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What is The Most Commonly Asked Question in Reliability Consulting?

• How many samples do I need to estimate B10 life?

(B10 is shorthand for the 10<sup>th</sup> percentile of life)

• And for how long do I need to run the test?

#### Answer to the Questions

**Literal:** Assuming a two-parameter Weibull lifetime distribution, test two units; wait until just after one of them fails.

**Practical:** It depends on how much precision you need! How wide do you want your confidence interval to be?

## Overview

- Confidence intervals and sample size for B-life basic ideas (cf Stat 101).
- Test plan for a *simple life test* (no regression)
- Test plan for an *accelerated life test* (simple regression with censored data).
- Test plan for an accelerated *destructive degradation test* (nonlinear regression).
- Test plan for *repeated measures degradation test* (mixed effects regression model).

### **Computation of Confidence Intervals**

Stat 101: 
$$\begin{bmatrix} \mu \\ \tilde{\mu} \end{bmatrix} = \overline{x} \pm z_{(1-\alpha/2)} s/\sqrt{n} = \overline{x} \pm d$$

d is the *half-width* of the confidence interval.

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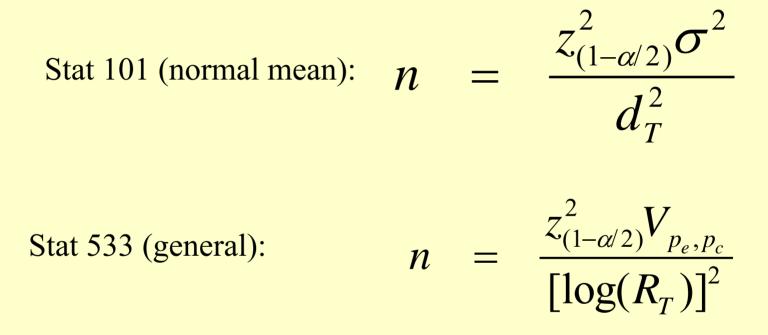
Stat 533: 
$$\begin{bmatrix} t_p, \tilde{t}_p \end{bmatrix} = \begin{bmatrix} \hat{t}_p/R, \hat{t}_p \times R \end{bmatrix}$$

R > 1 is a *precision factor*. If R=2 and , then the CI is  $[7/2, 7 \times 2] = [3.5, 14]$ .

#### Sample Size Formulas

Stat 101 (normal mean):  $n = \frac{z_{(1-\alpha/2)}^2 \sigma^2}{d_T^2}$ 

#### Sample Size Formulas

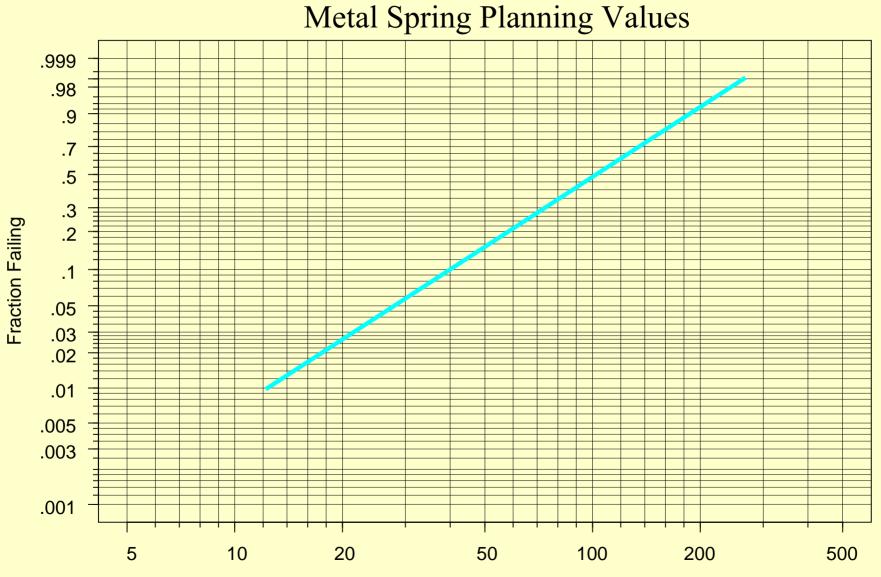


Note: Need planning information.

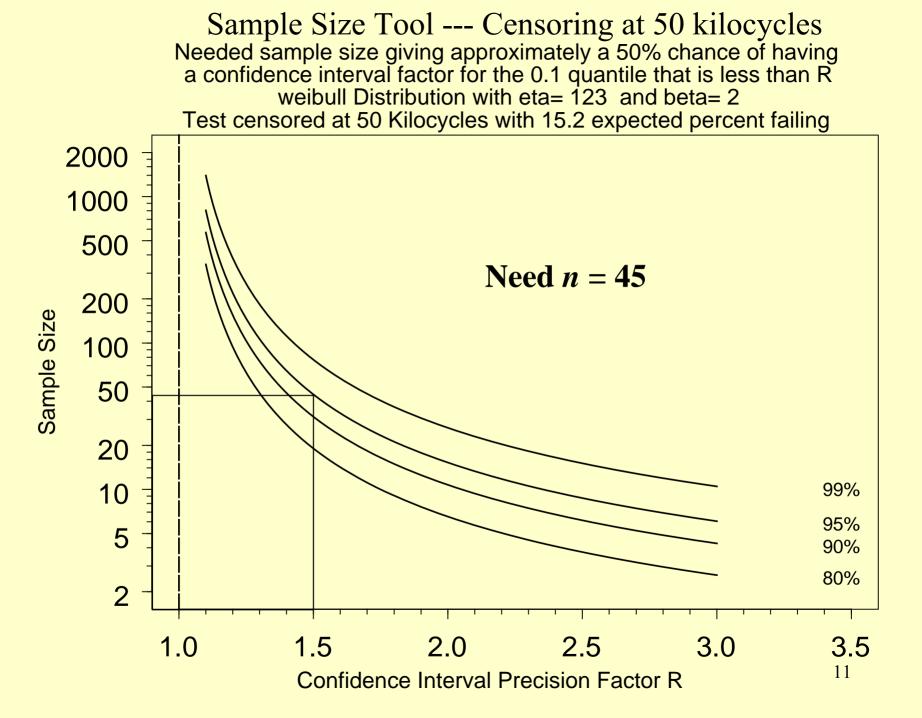
## Planning a Life Test for a Metal Spring

- Want to estimate B10 of spring life
- Planning information
   Weibull distribution
   Weibull shape β = 2
   B10 = 40 thousand cycles
- Time censoring at 30 or 50 thousand cycles

Weibull Distribution with eta= 123.2 and beta= 2 Weibull Probability Plot

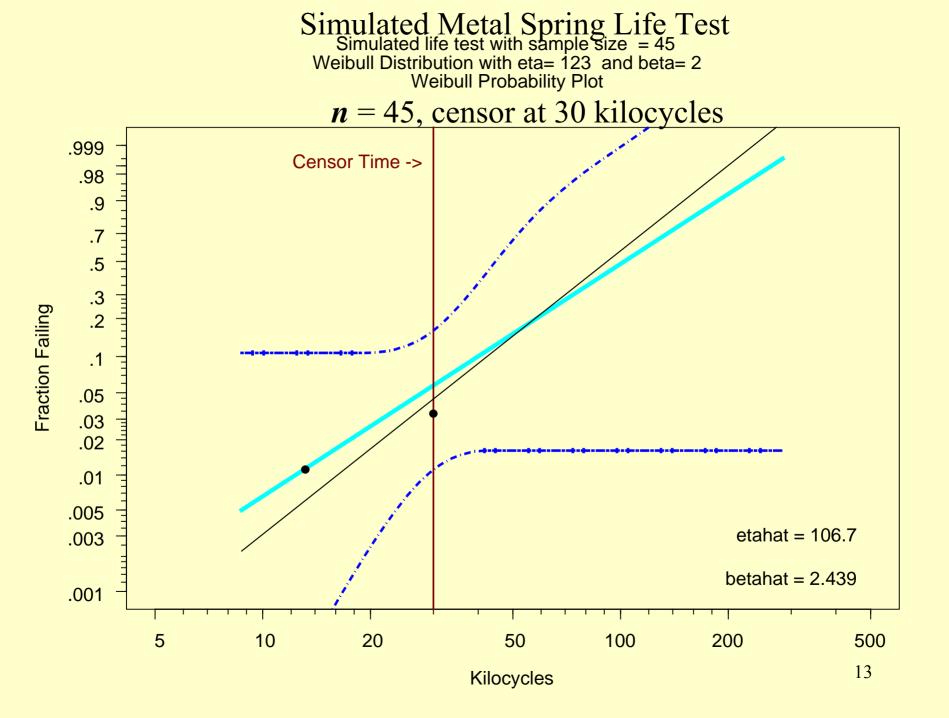


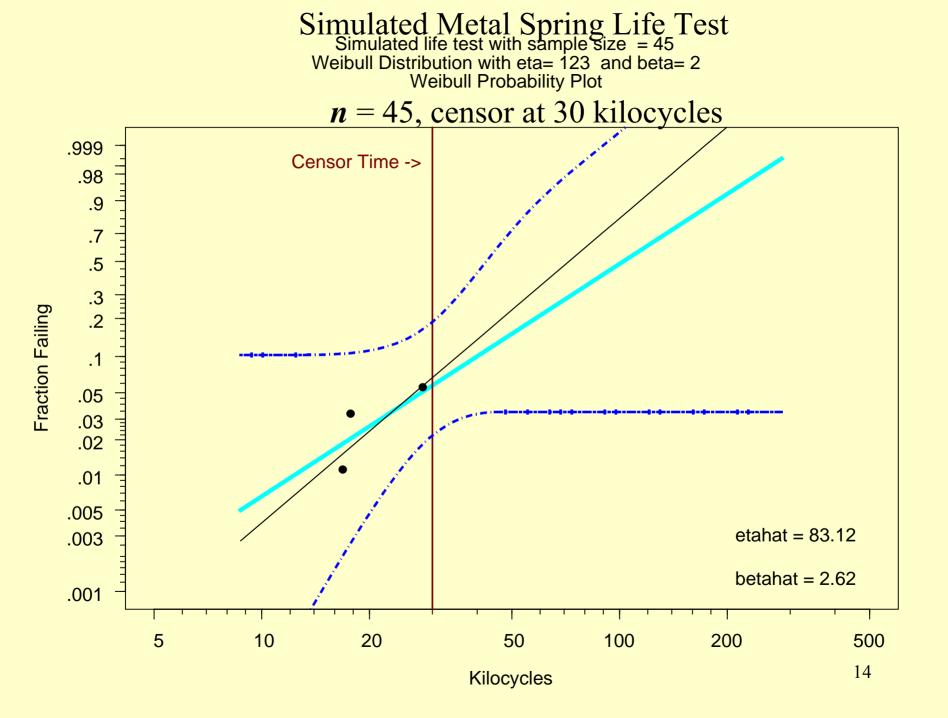
**Kilocycles** 

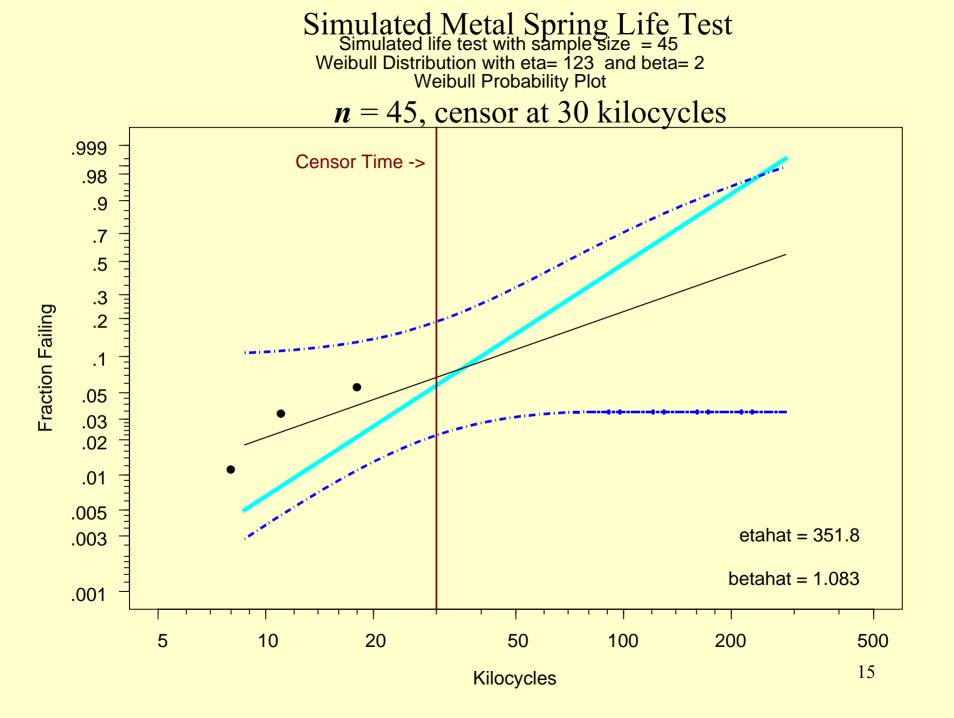


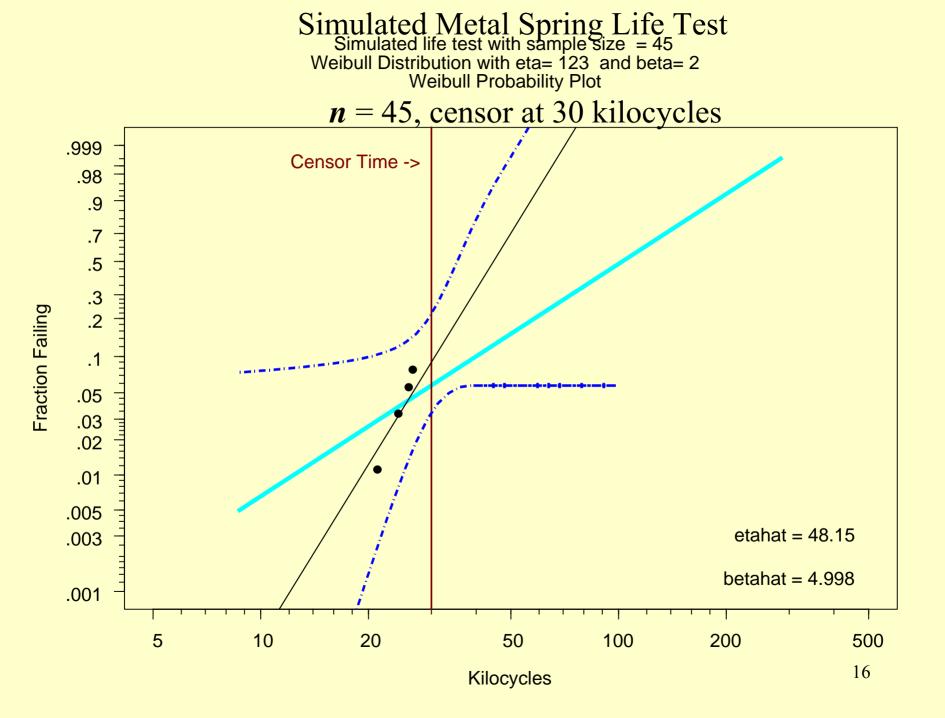
# General Strategy for Test Planning: Anticipate Test Results

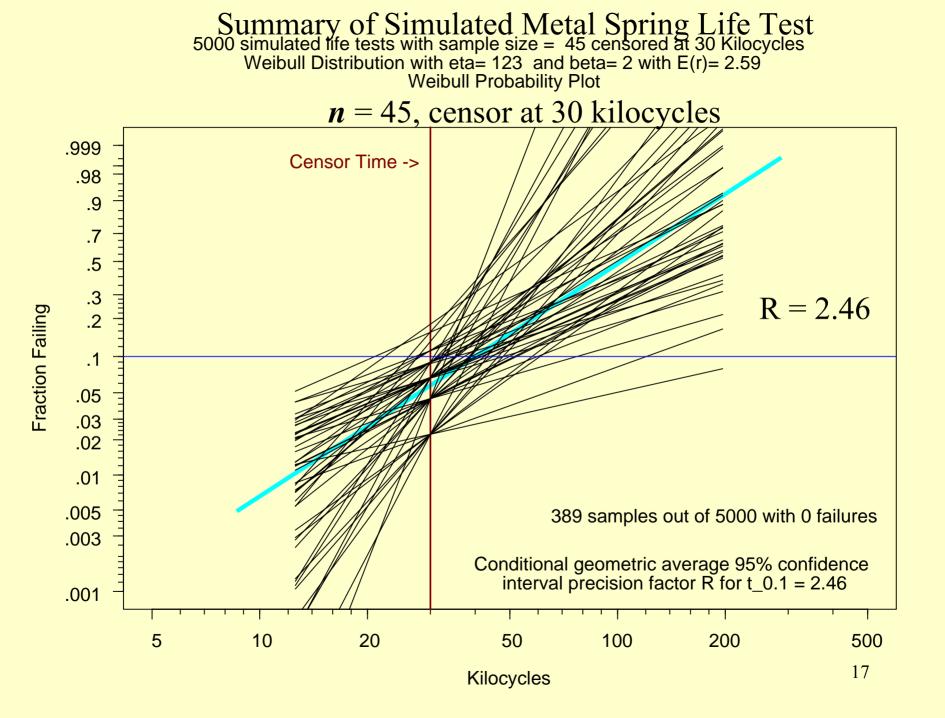
- Elicit planning information
- Use sample size tool (large sample approximation)
- Possibly optimize plan using large-sample approximation
- Simulate test test plan to provide
  - □ Visualization
  - Insight
  - □ Evaluation without approximation

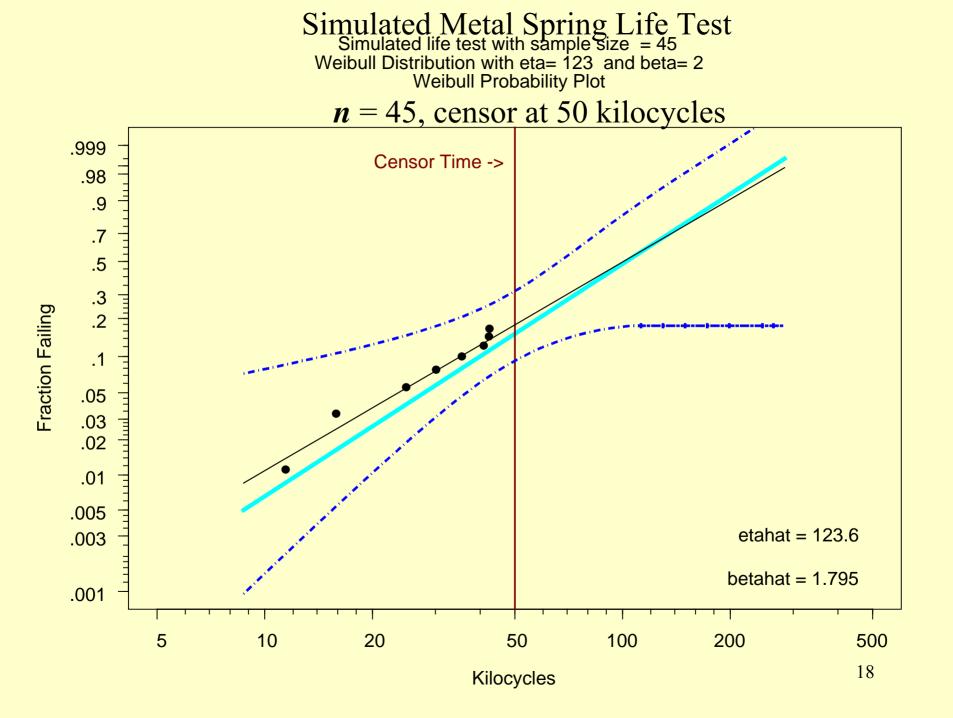


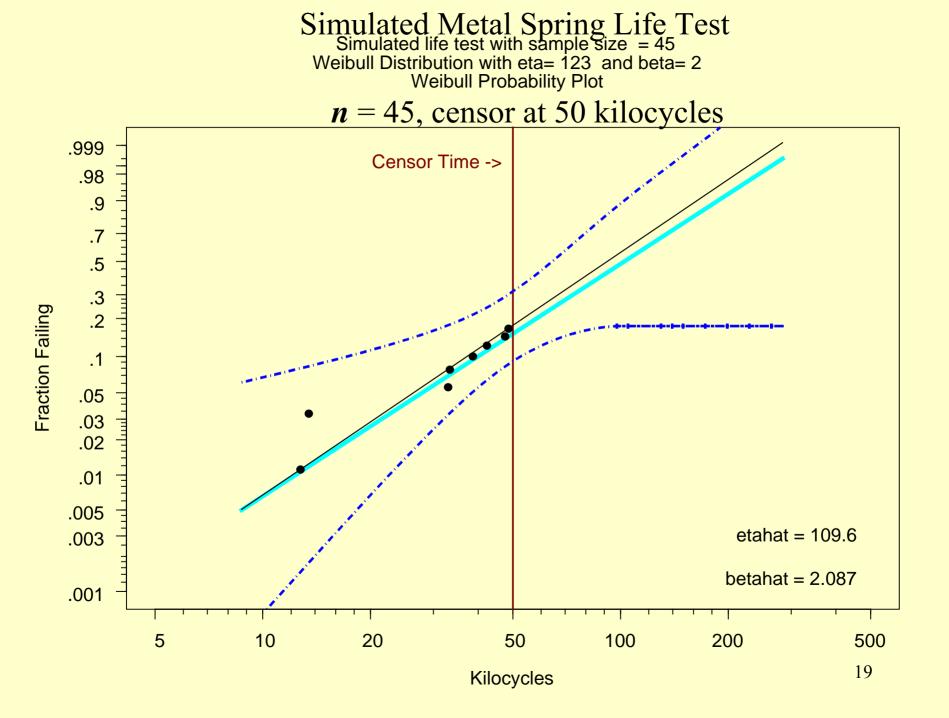


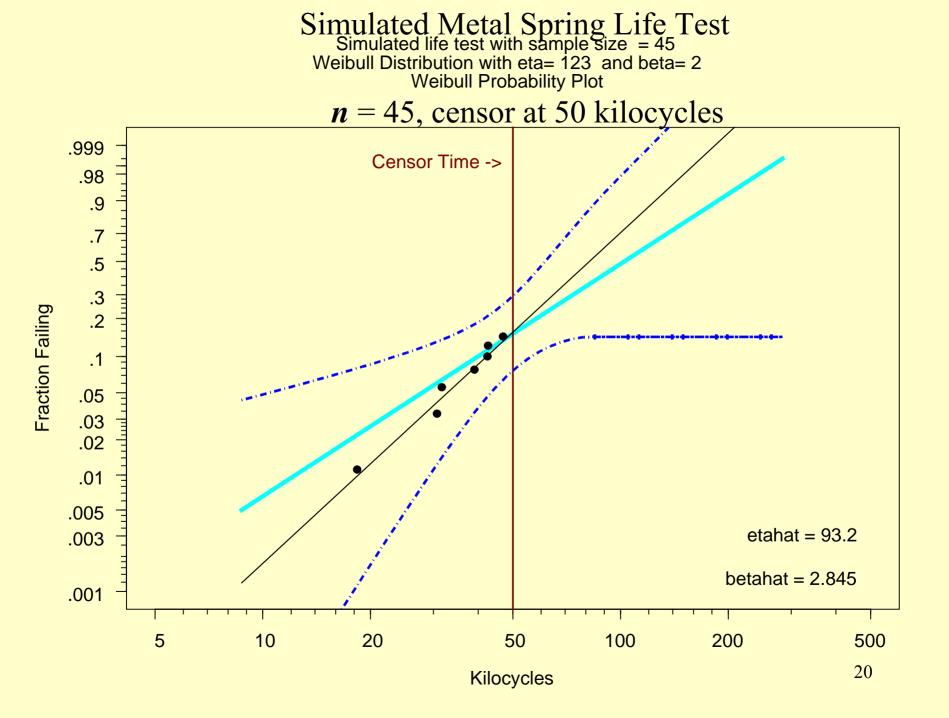


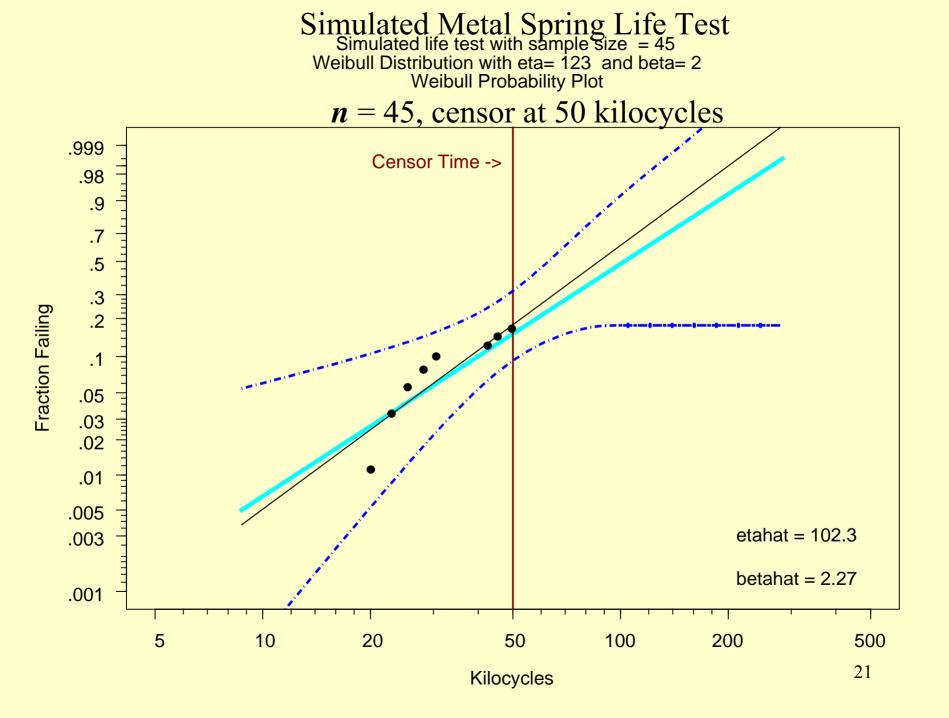


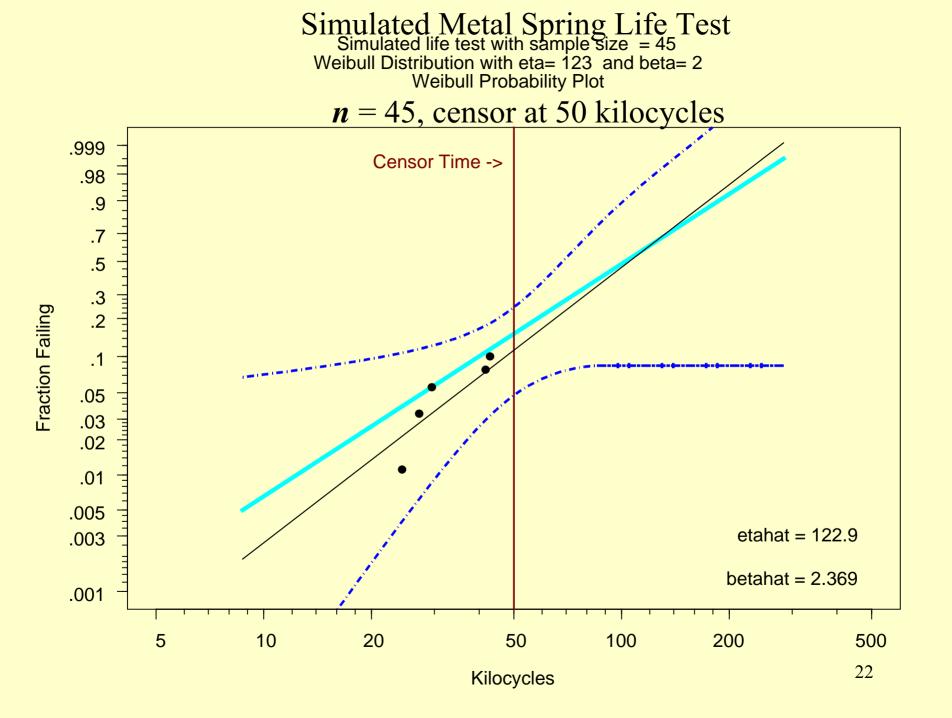


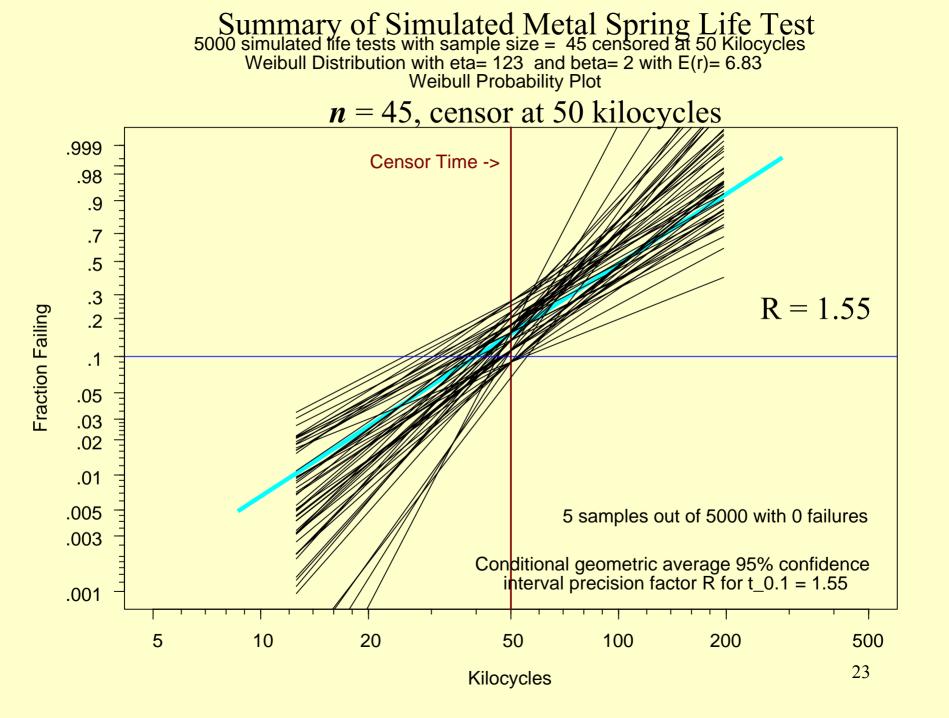


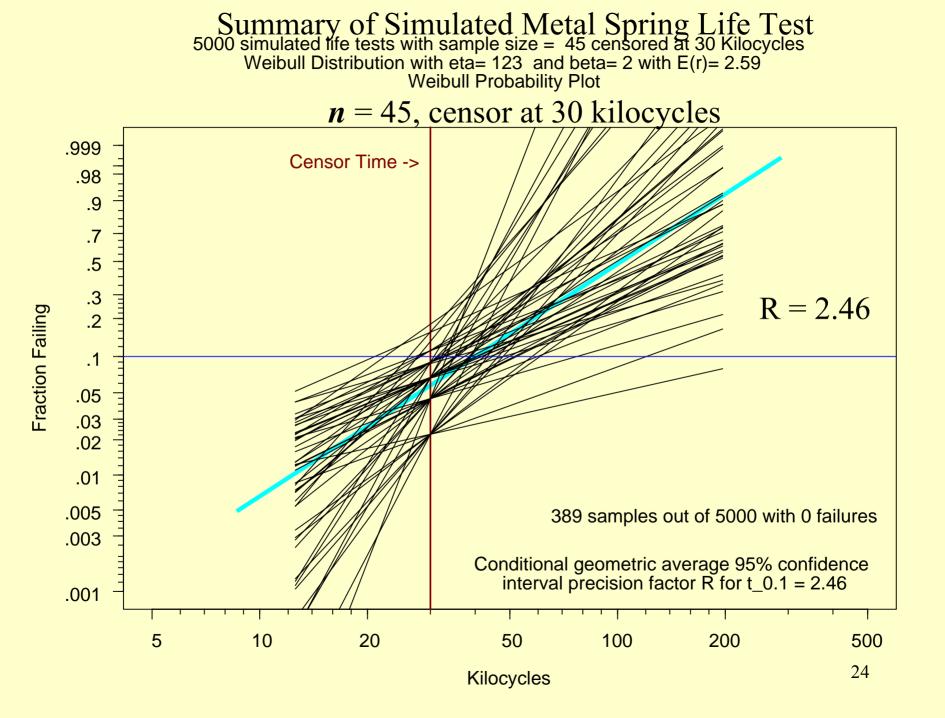


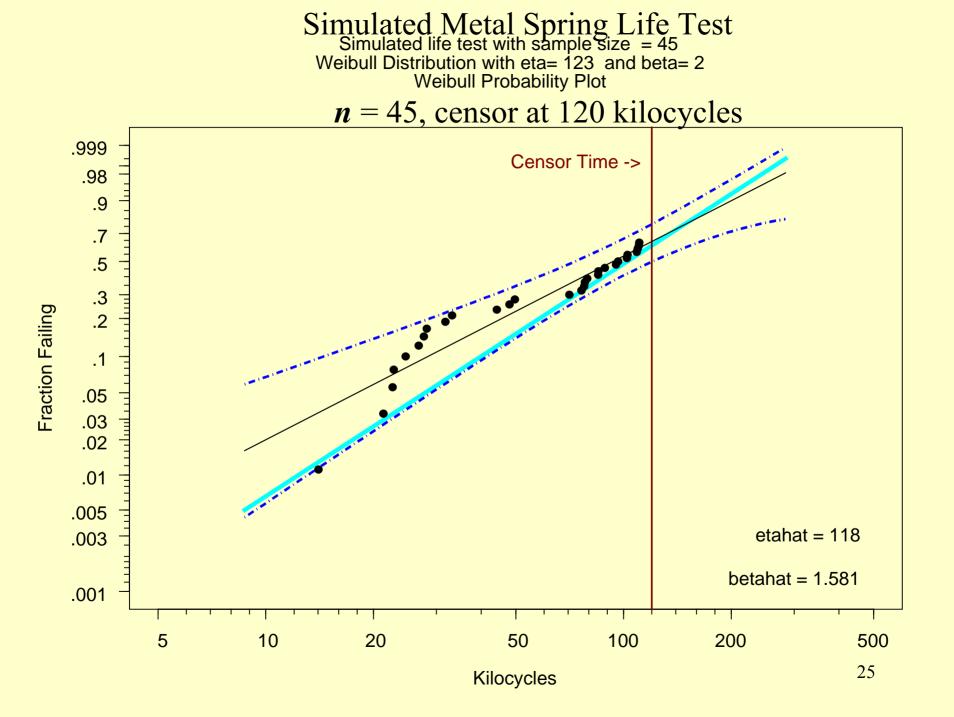


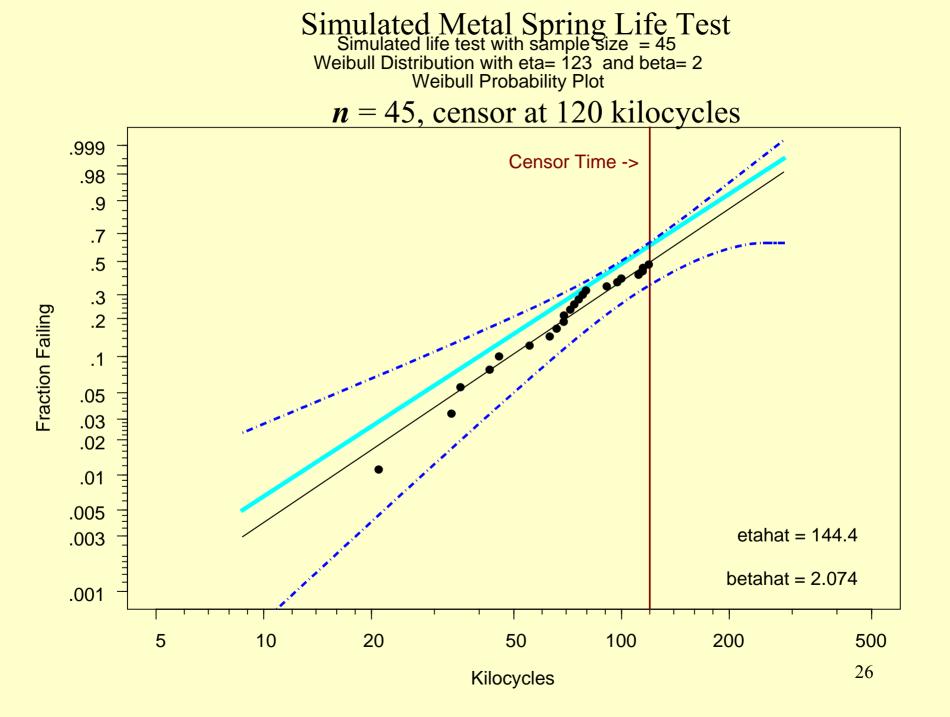


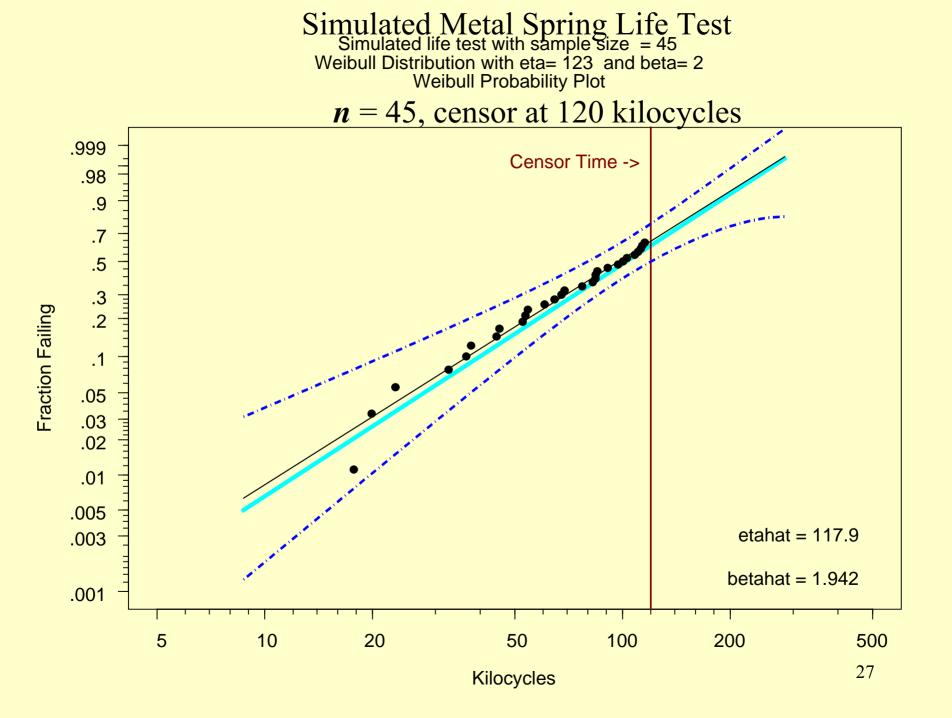


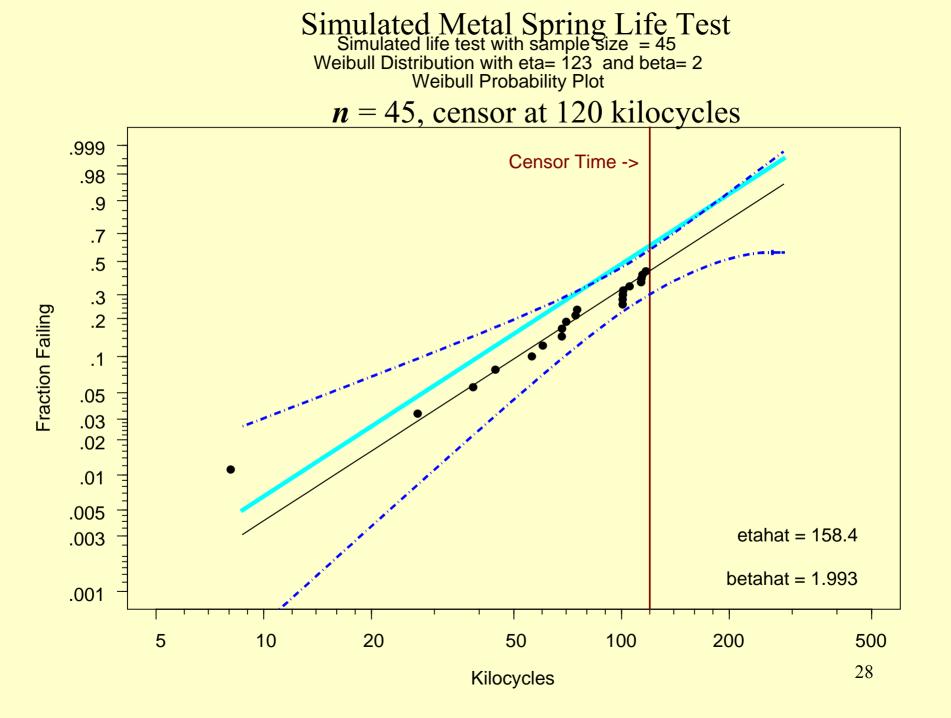


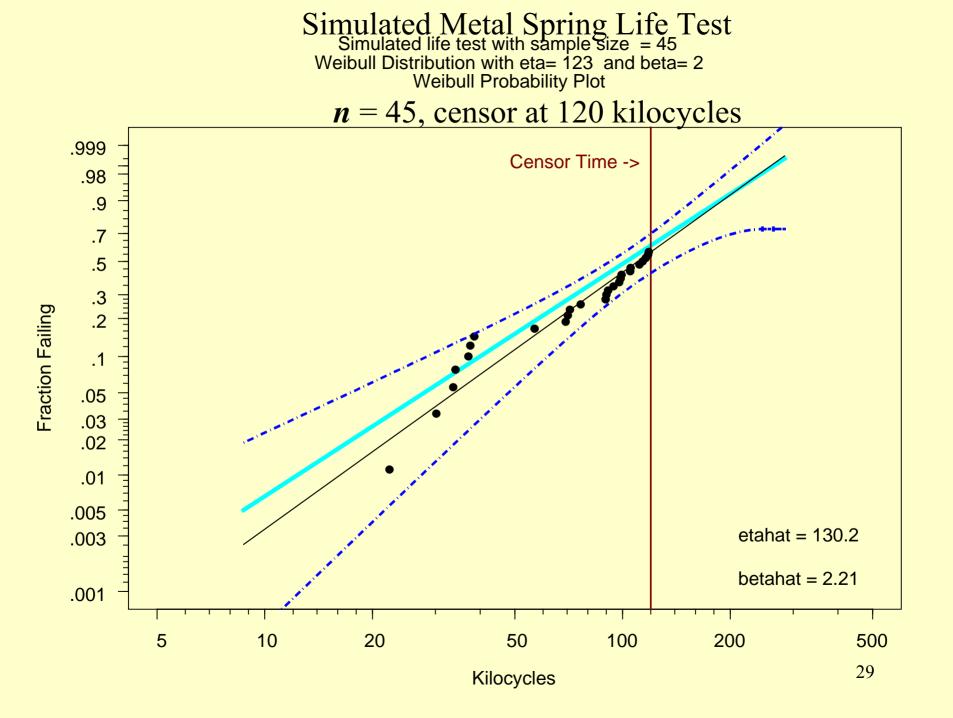


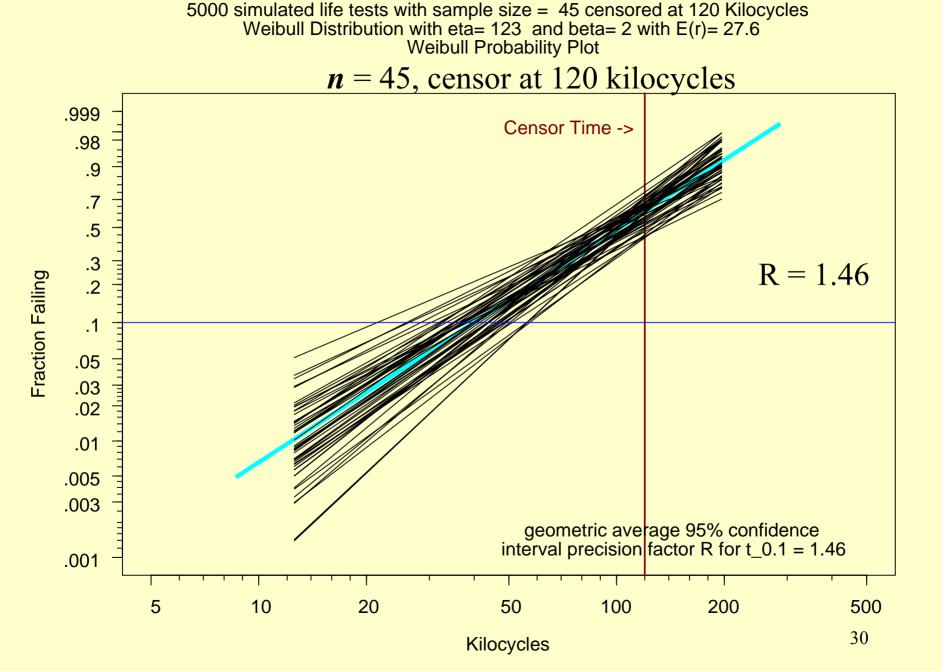


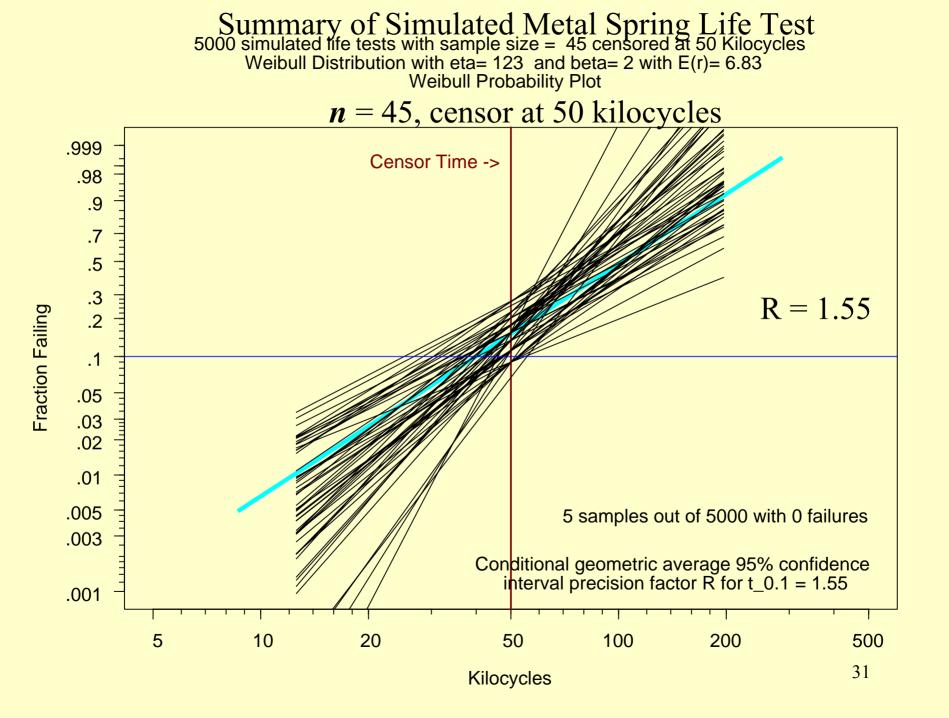




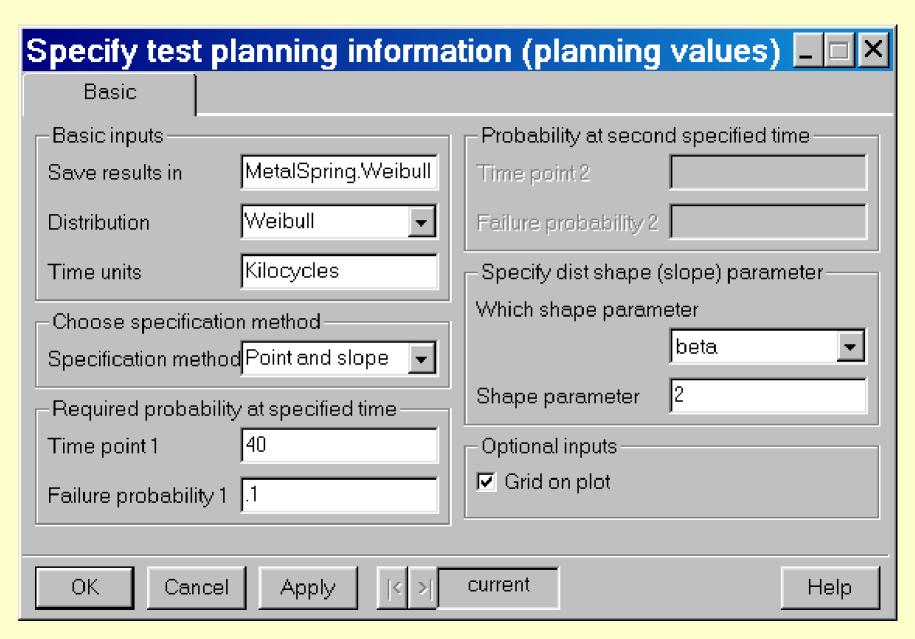








h	<u>S</u> plida O <u>p</u> tions <u>W</u> indow <u>H</u> elp		
	SPLIDA (S-PLUS Life Data Analysis)		
	Copyright 1995-2005 W.Q. Meeker		
	SPLIDA (S-PLUS Life Data Analysis) Version 6.7.4, August 3, 2005		
	Make/edit/summary/view data object	►	
	LIFE DATA SINGLE DISTRIBUTION		
iul	Plan a single distribution study	•	Specify test planning information (planning values)
.01	Single distribution data analysis	►	Plot test planning information (planning values)
, Se	Single distribution Bayesian analysis	►	Plot of approximate required sample size
	Multiple failure mode data analysis	►	Simulate a life test
	LIFE DATA COMPARISON AND REGRESSION		Probability of successful demonstration
	Comparison of distributions life data analysis	•	
	Plan an accelerated life test (ALT)	►	
ons	Simple regression (ALT) data analysis	►	
1.6	Multiple regression (ALT) data analysis	►	
	RECURRENCE DATA		
ave	Recurrence (point process) data analysis	►	
	REPEATED MEASURES DEGRADATION DATA		
3 5	Repeated measures degradation (RMDeg) data analysis	►	
3 1	DESTRUCTIVE DEGRADATION DATA		
	Plan an accelerated destructive degradation test (ADDT)	►	
	Accelerated destructive degradation test (ADDT) analysis	►	
	SPLIDA SPECIAL TOOLS AND MODELS		
	Special models	•	
	Splida tools	•	
	Change SPLIDA default options (preferences)		

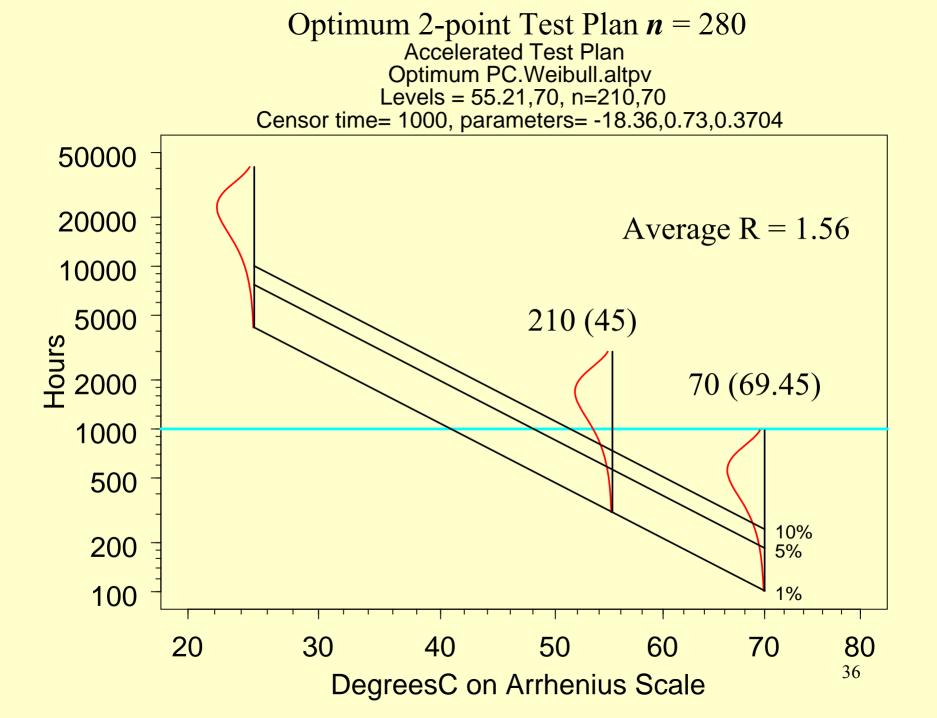


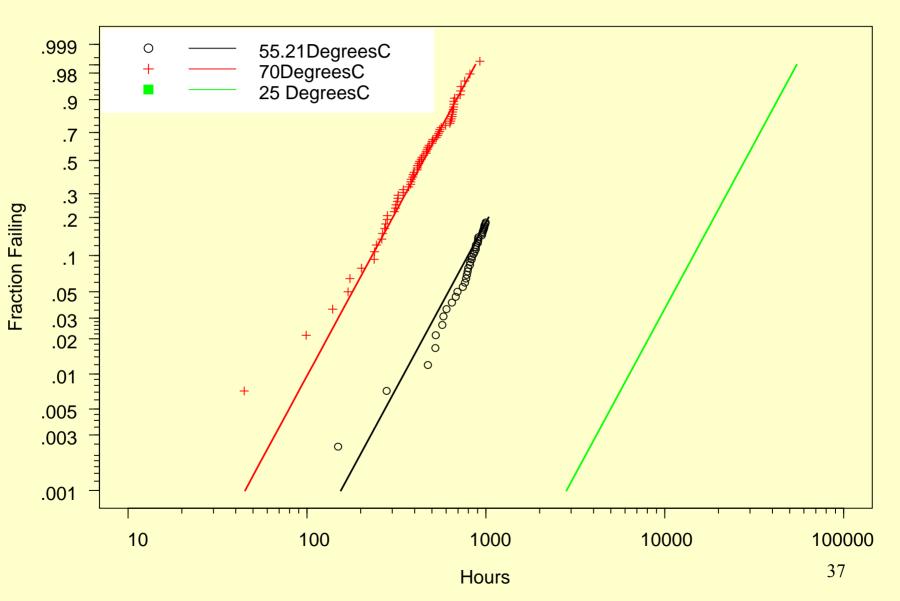
#### Simulate a life test

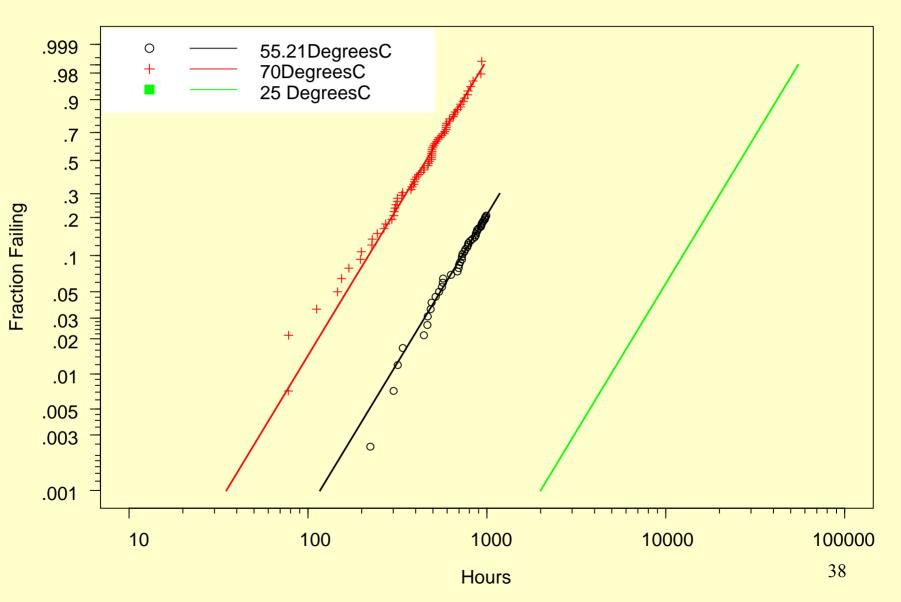
Simulate a life test					
Basic Plot options					
Required inputs Plan values object MetalSpring.Wei  Refresh list(s)	Some Options Quantile line at 0.1				
Sample size 45	Number of simulations				
Censoring type and specification	Number of lines to plot				
Type of censoring Time (Type I)	50				
Censoring time     50       Number of failures	View detail for how many samples				
	Save results in MetalSpring.Weibull				
OK Cancel Apply  < >  current Help					

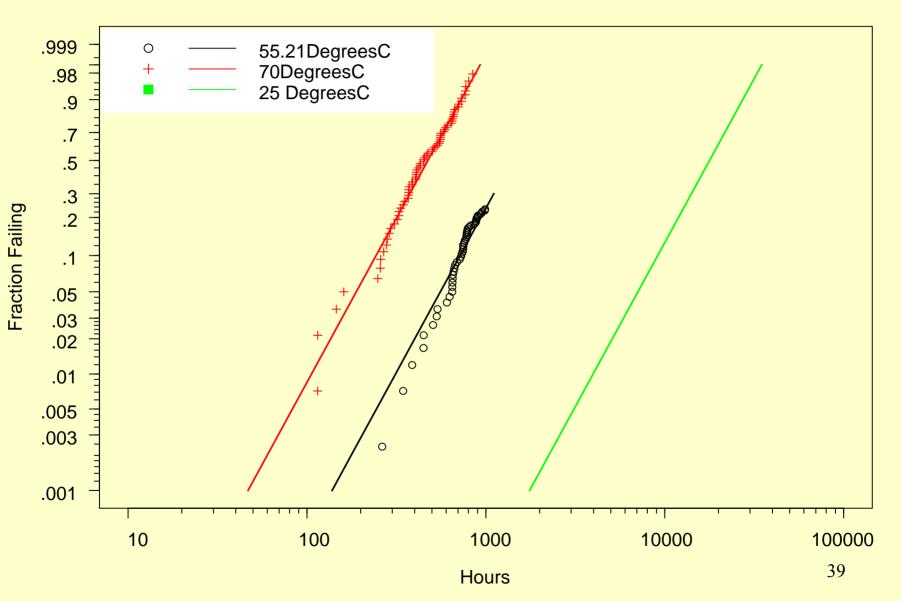
Planning an *Accelerated Life Test* for a Protective Coating for a Circuit Board

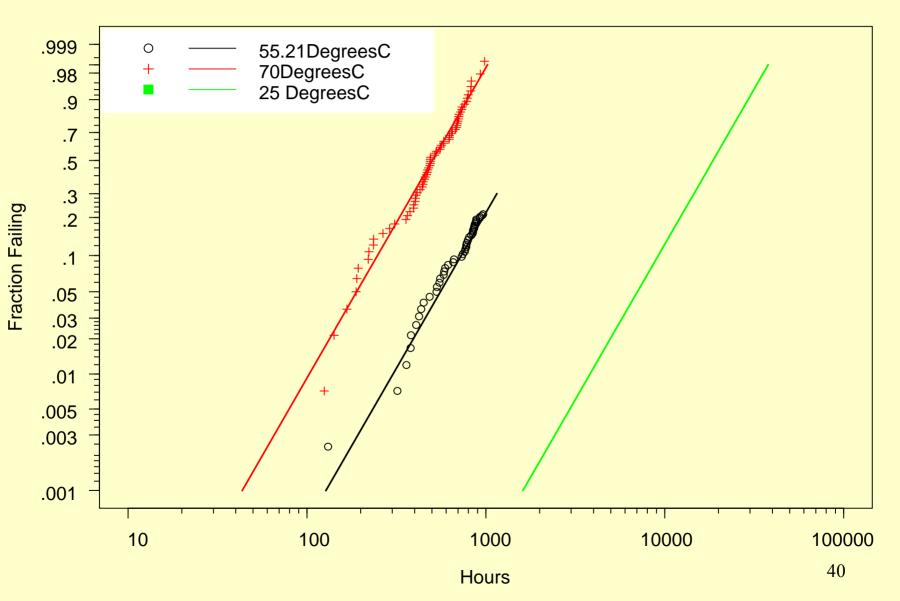
- Want to estimate B01 life at 25 Degrees C
- Can test at temperatures up to 70 Degrees C
- Planning values
  - $\Box$  Weibull distribution with shape  $\beta = 2.7$
  - $\Box$  Activation energy = 0.73 eV
  - $\square$ B01.2 = 500 hours at 50 Degrees C
- Time censoring required at 1000 hours
- Can test 280 units

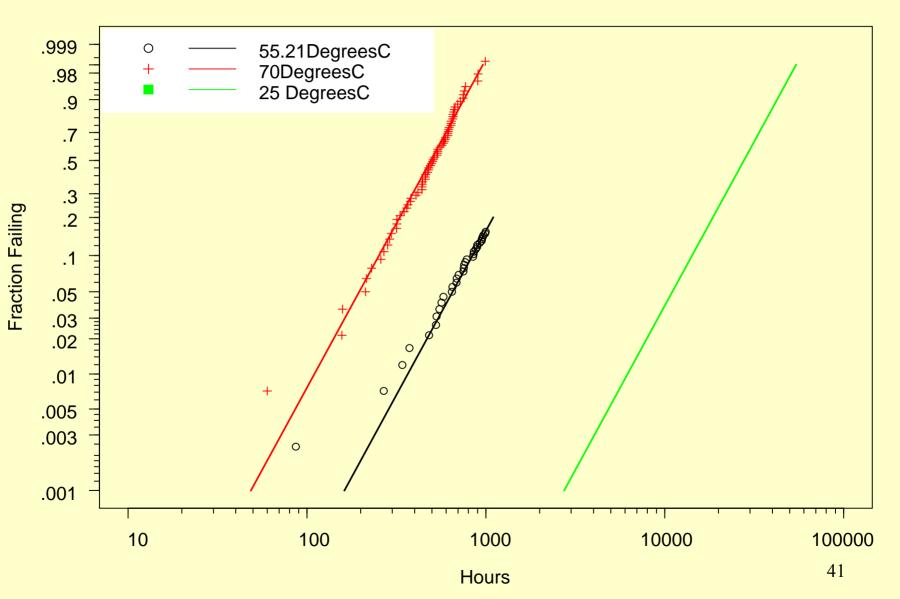


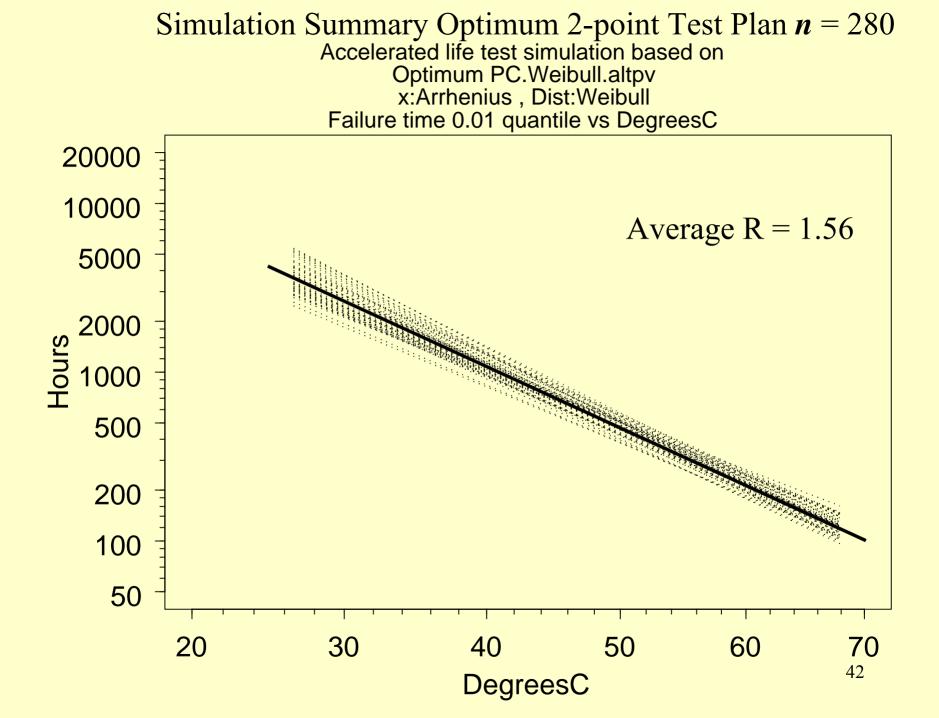


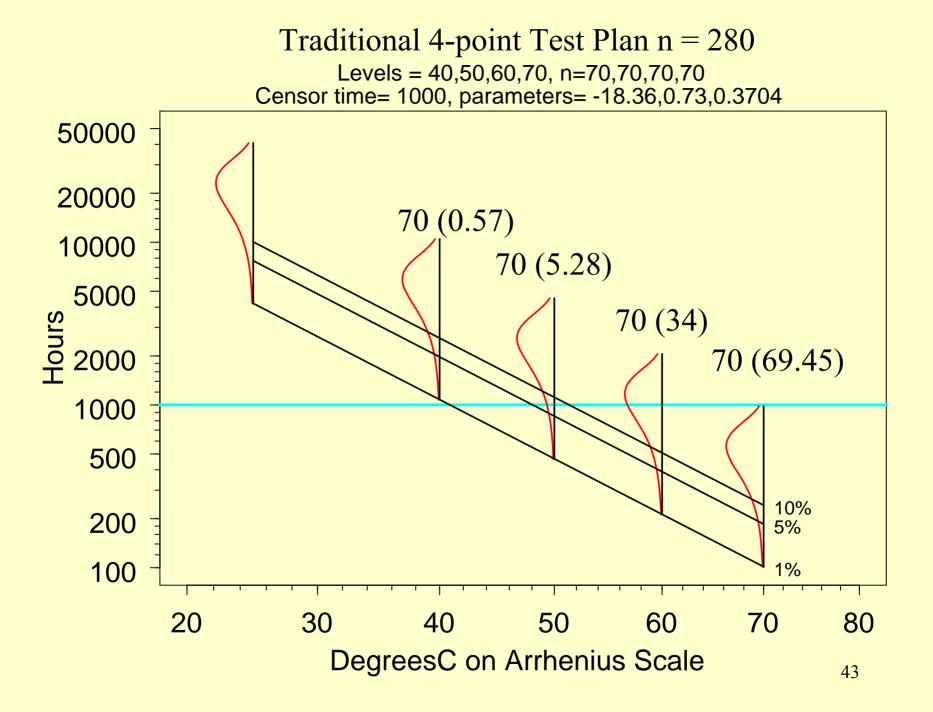




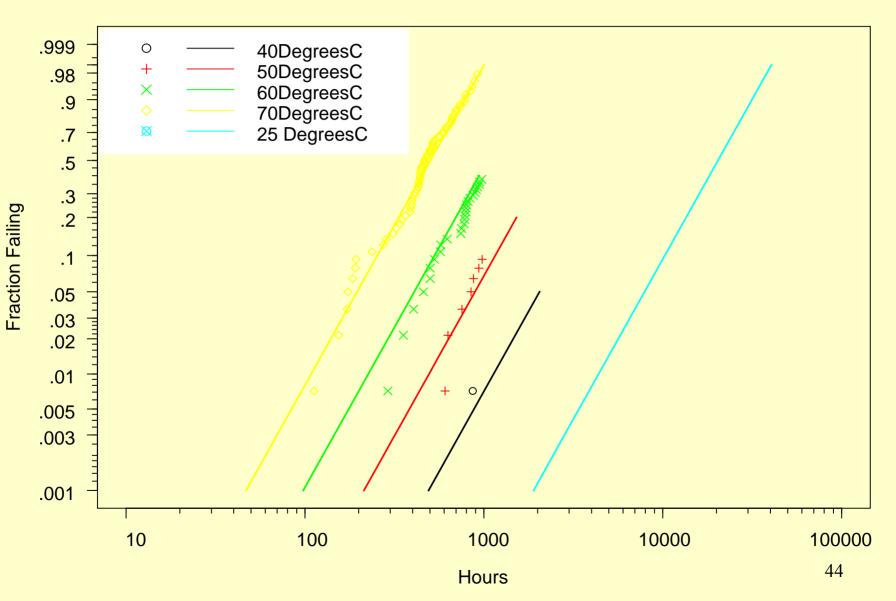




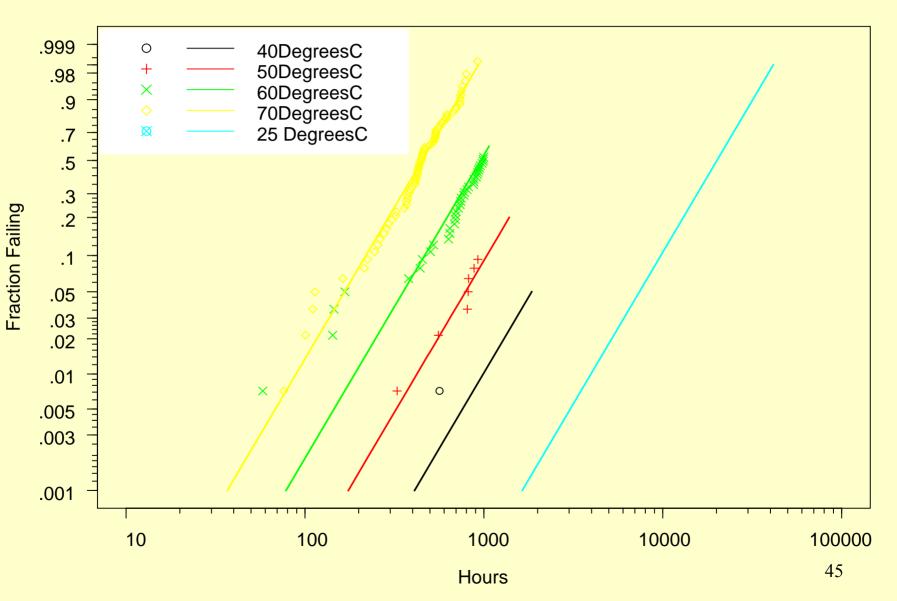




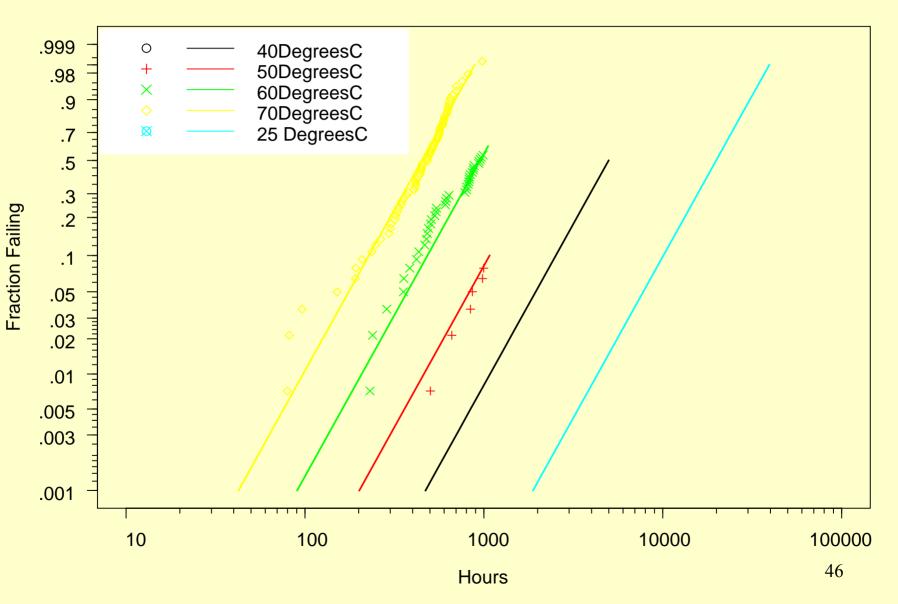
# $\begin{array}{l} Traditional \ 4-point \ Test \ Plan \ n=280\\ \ Simulated \ data \ from \ Trad4.ALT plan \ PC.Weibull.altpv \ Model \ MLE\\ \ Degrees CArrhenius, \ Dist:Weibull\\ \ Weibull \ Probability \ Plot \end{array}$



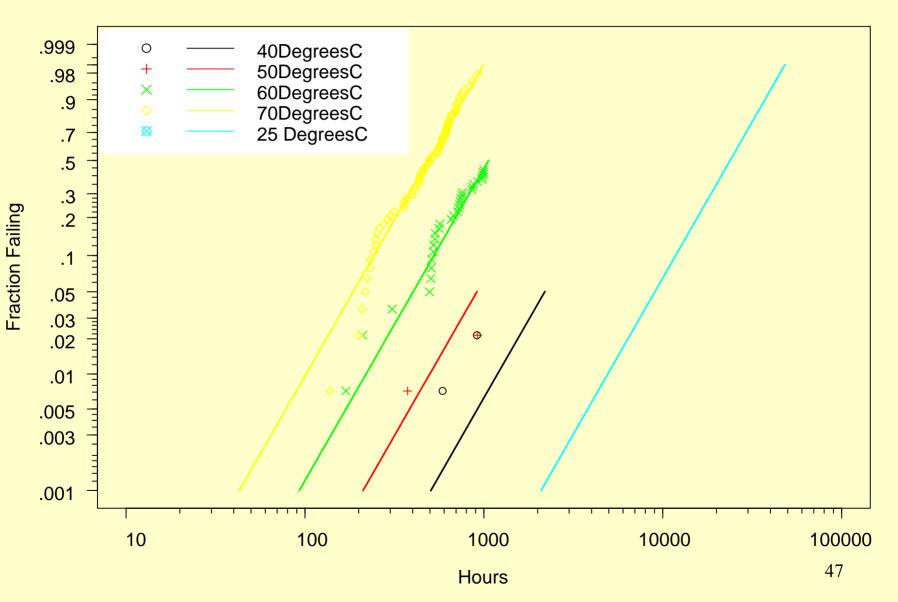
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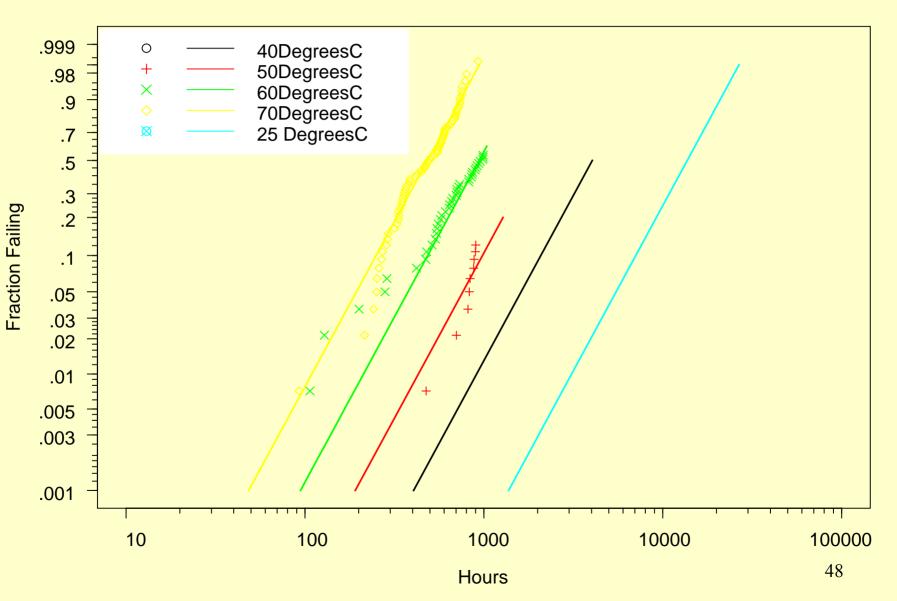
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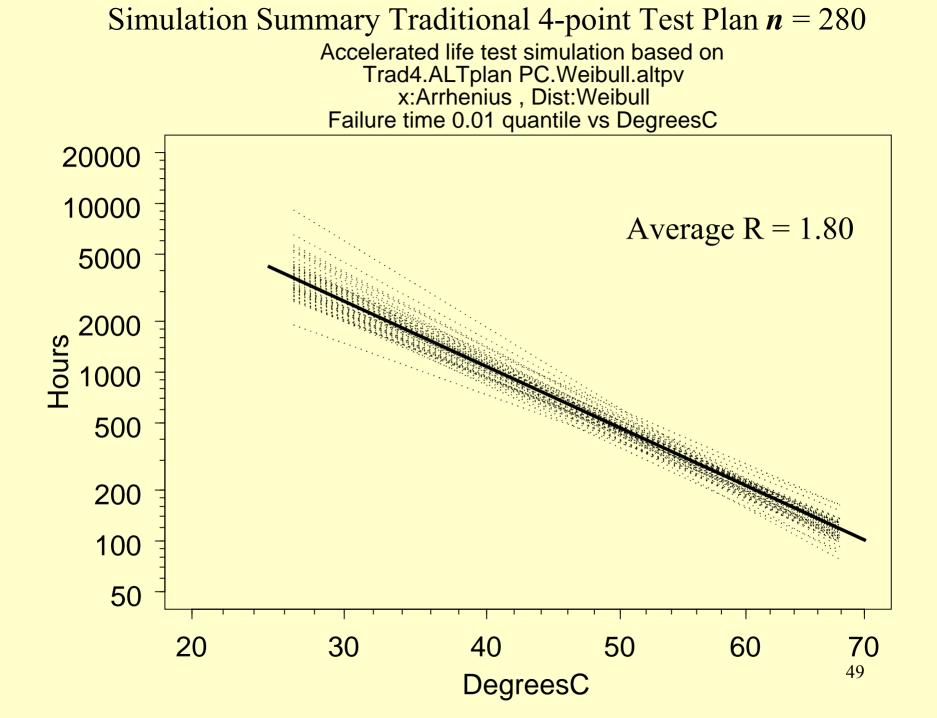


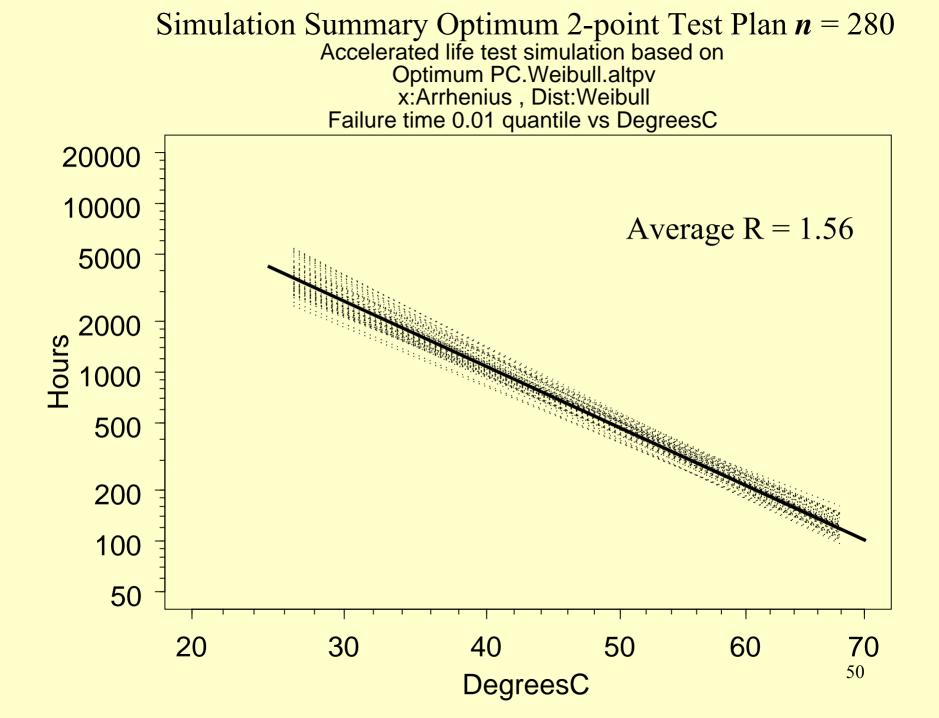
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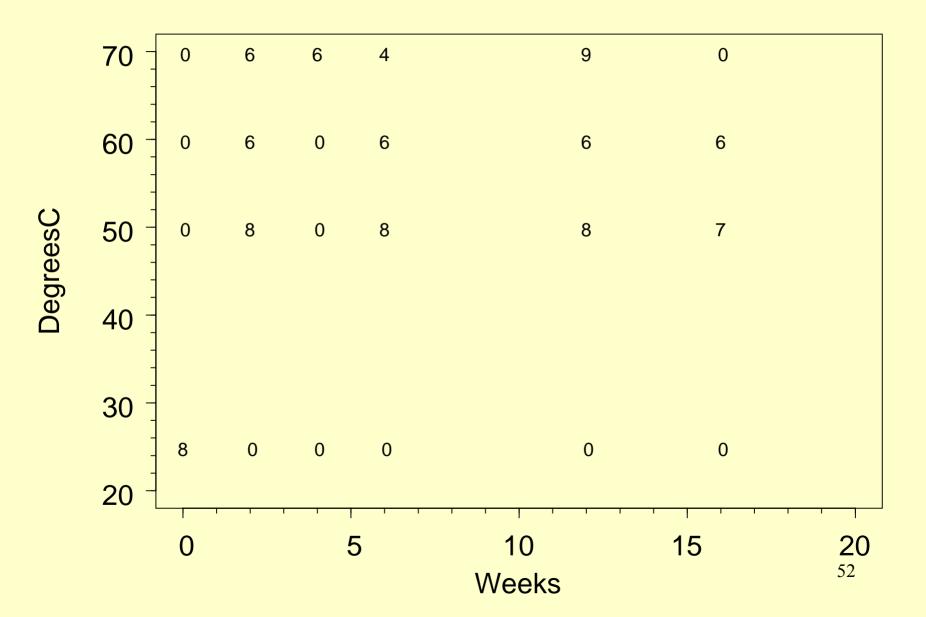


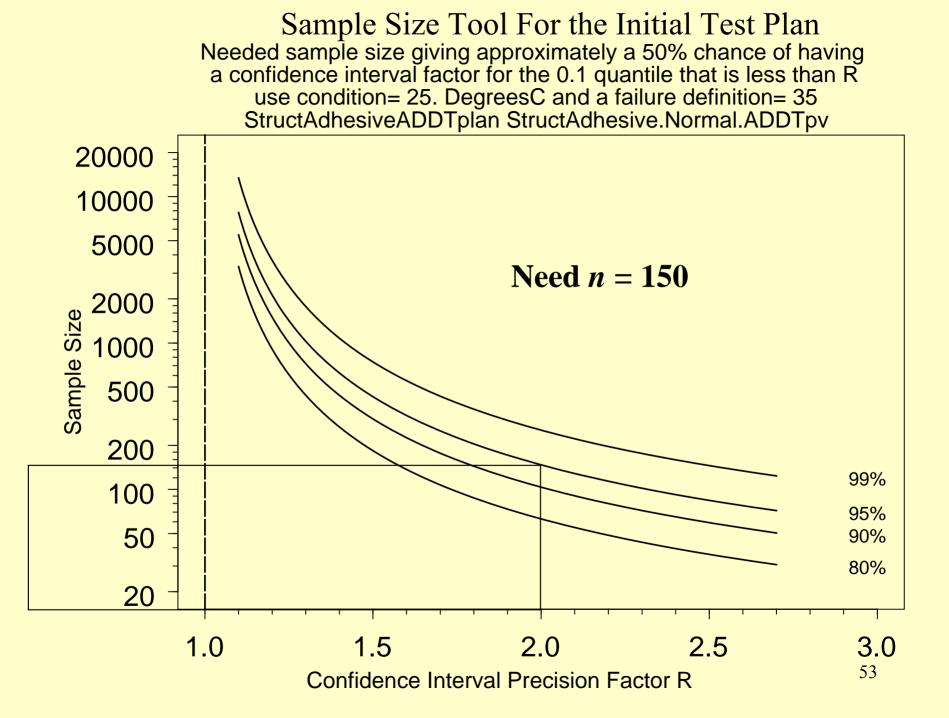


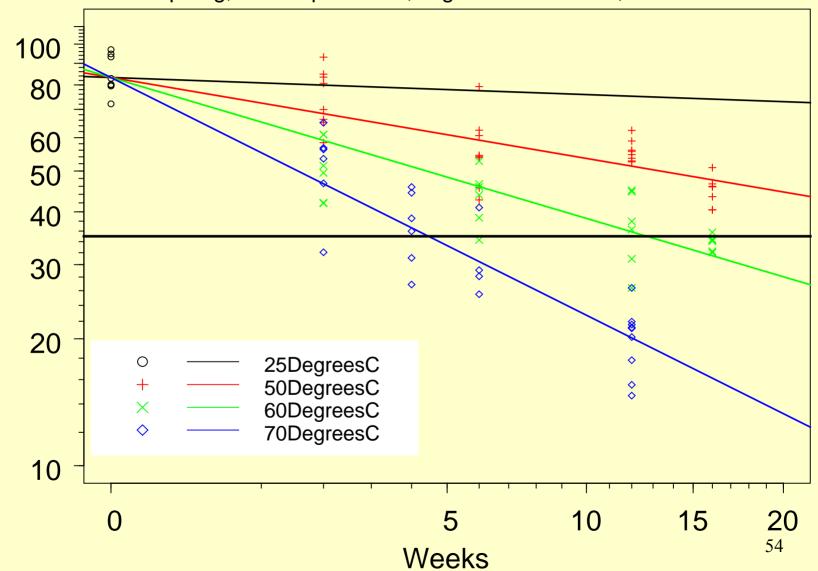
#### Planning an Accelerated Destructive Degradation Test for an Adhesive Bond

- Want to estimate B10 life at 25 Degrees C (260 week goal)
- Can test at temperatures up to 70 Degrees C
- Log strength is linear in square root of time
- Failure is defined as strength < 35 Newtons
- Planning values for strength (Weeks, Degrees C) distribution
  Log strength distribution is normal with σ = 2.7
  Median strength at time 0 is 78.3 Newtons
  Log strength rate of change is -0.12 at 50 Degrees C
  Effective activation energy = 0.58 eV
- Time censoring required at 16 weeks
- Can test 88 units

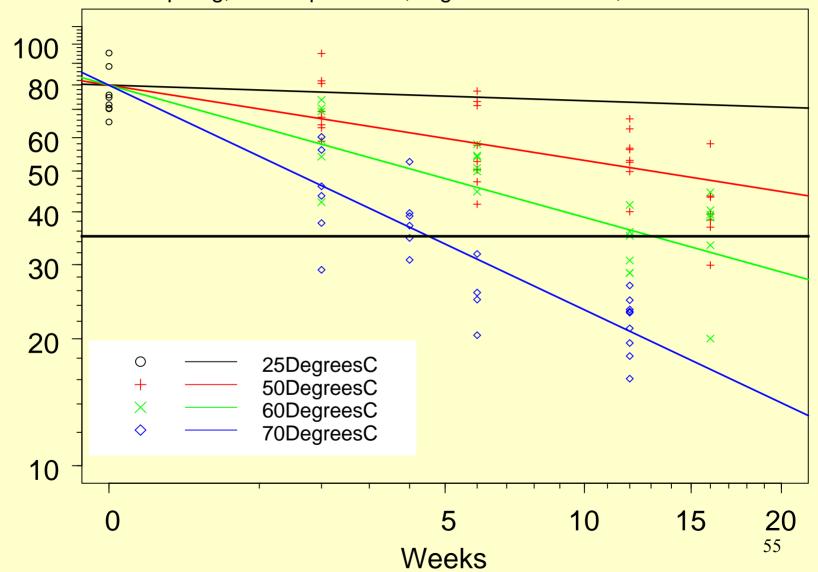
#### Initial Adhesive Bond Test Plan n = 88



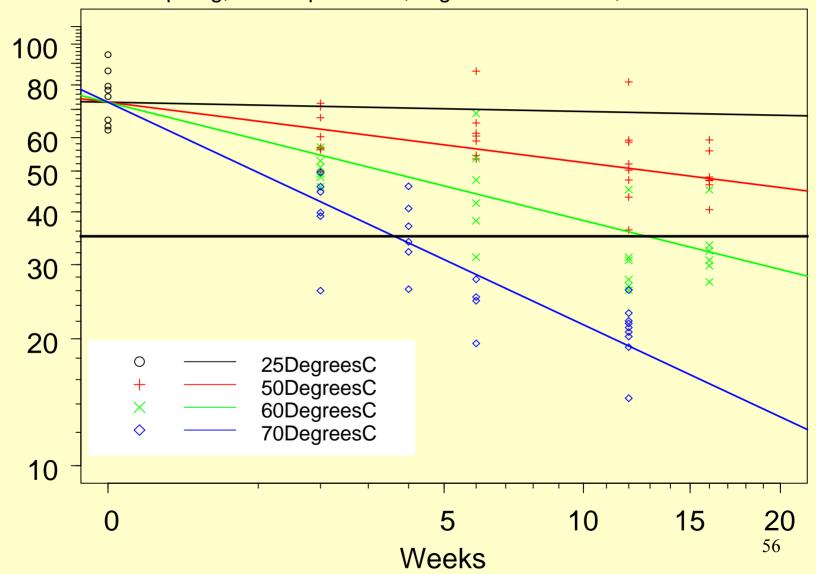




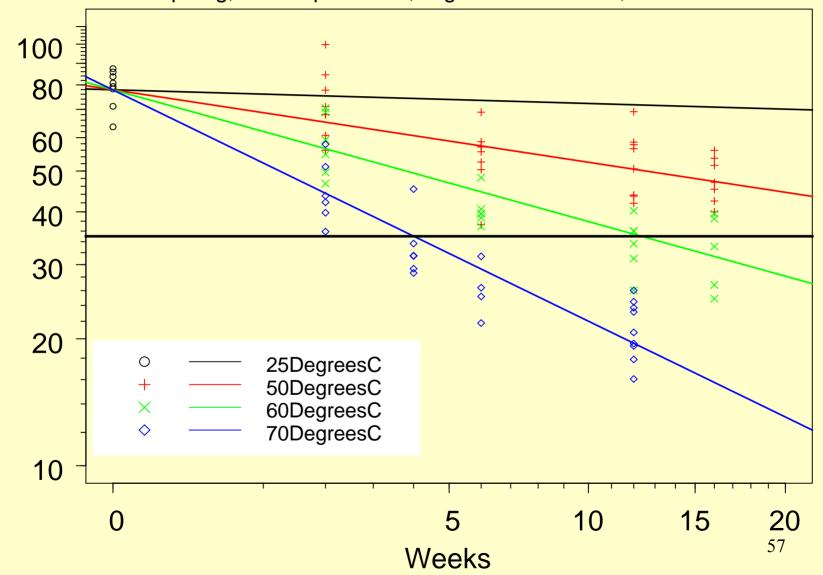
Newtons



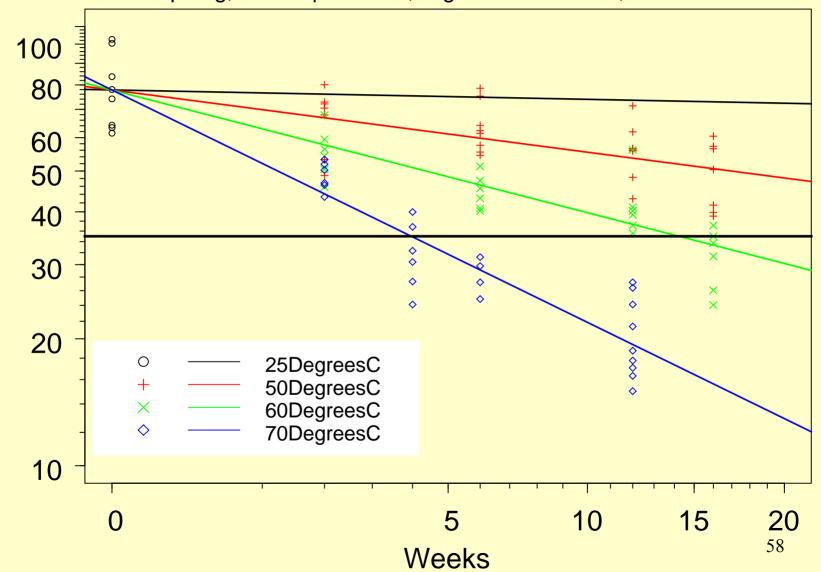
Newtons



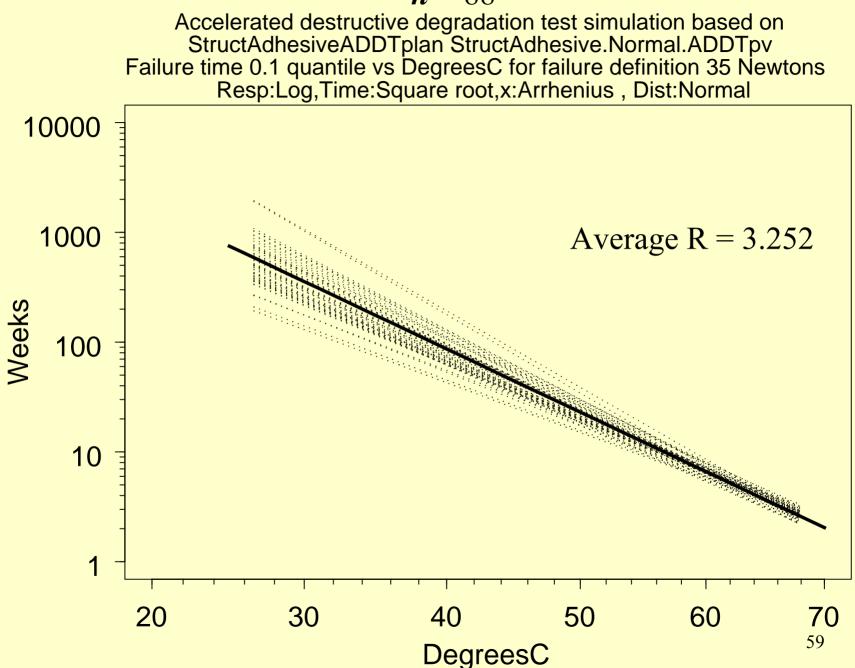
Newtons

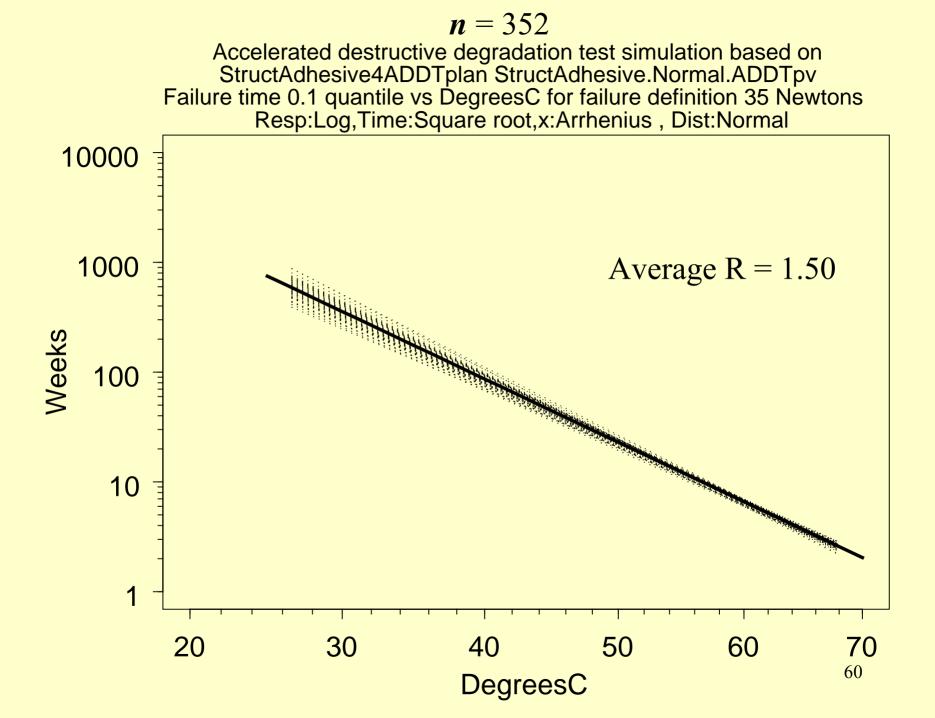


Newtons



Newtons





#### Accelerated destructive degradation test simulation based on StructAdhesive2ADDTplan StructAdhesive.Normal.ADDTpv Failure time 0.1 quantile vs DegreesC for failure definition 35 Newtons Resp:Log,Time:Square root,x:Arrhenius , Dist:Normal Average R = 1.989Weeks DegreesC

#### **Concluding Remarks**

- Analytical (large sample approximation) methods provide a useful tool for test plan *optimization* and approximate *sample size choice*.
- Simulation provides *visualization* and *insight* into reasons that a design has particular properties
- Modern computing and *graphical* tools make it possible to use these methods in concert.